

SASE FEL PULSE DURATION ANALYSIS FROM SPECTRAL CORRELATION FUNCTION

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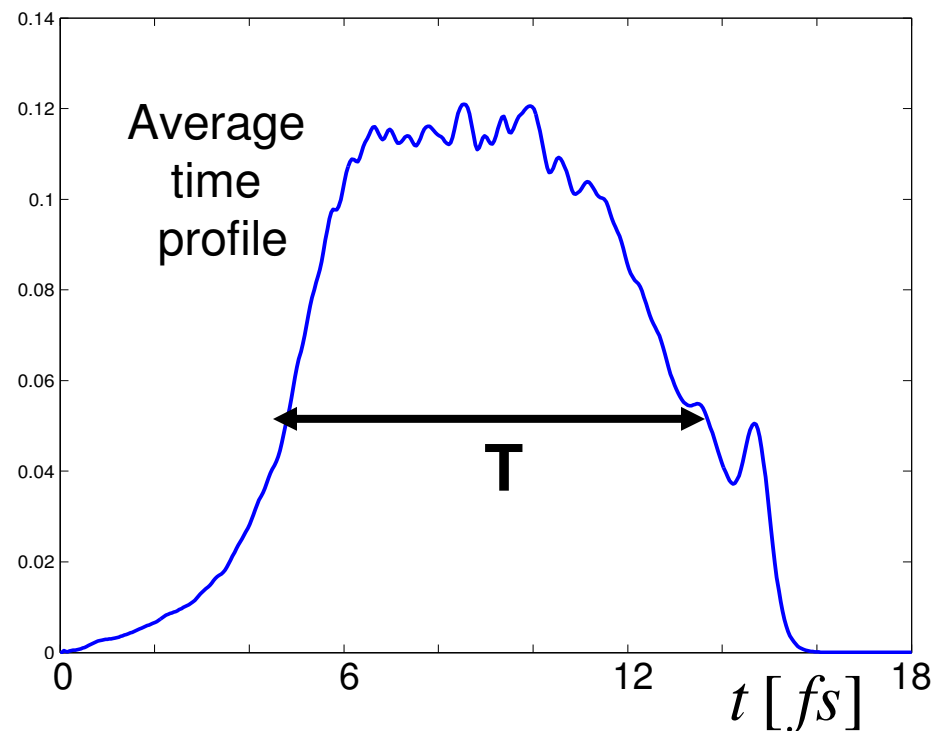
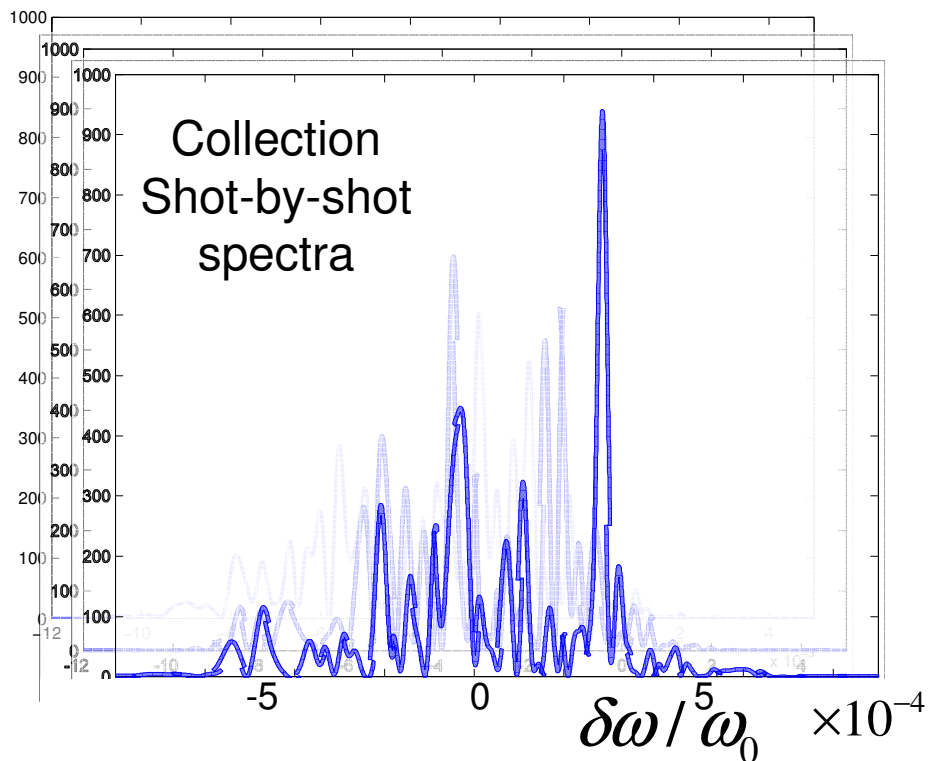


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X-ray pulse duration measurement



We recover the average x-ray
time profile length **T**
from a collection of single shot spectra

Model description

Electron beam current:

$$I(t) = (-e) \sum_{k=1}^N \delta(t - t_k)$$

t_k are independent random variables with probability density $f(t)$

SASE FEL Amplifier in linear regime:

$$E(t) = \int_{-\infty}^{+\infty} h(t, \tau) I(\tau) d\tau = \int_{-\infty}^{+\infty} h_{ii}(t - \tau) h_{td}(\tau) I(\tau) d\tau$$

$$h_{ii}(t - \tau) = A_0(z) e^{i(k_0 z - \omega_0(t - \tau))} e^{-\frac{(t - \tau - z/v_g)^2}{4\sigma_t^2}} \left(1 + \frac{i}{\sqrt{3}}\right)$$

time independent

$$h_{td}(\tau) \quad \text{time dependent}$$

Model description

Electric field spectrum:

$$\tilde{E}(\omega) = (-e)\tilde{H}_{ti}(\omega) \sum_{k=1}^N h_{td}(t_k) e^{i\omega t_k}$$

Average x-ray profile:

$$X(t) = |h_{td}(t)|^2 f(t)$$

First and second order correlations

$$\langle \tilde{E}(\omega') \tilde{E}^*(\omega'') \rangle = e^2 N \tilde{H}_{ti}(\omega') \tilde{H}_{ti}(\omega'') \tilde{X}(\omega' - \omega'')$$

$$\langle |\tilde{E}(\omega')|^2 |\tilde{E}(\omega'')|^2 \rangle = e^4 N^2 |\tilde{H}_{ti}(\omega')|^2 |\tilde{H}_{ti}(\omega'')|^2 \left(\tilde{X}(0) + |\tilde{X}(\omega' - \omega'')|^2 \right)$$

Model description

First and second order correlations functions

$$g_1(\omega', \omega'') = \frac{\langle \tilde{E}(\omega') \tilde{E}^*(\omega'') \rangle}{\sqrt{\langle |\tilde{E}(\omega')|^2 \rangle \langle |\tilde{E}(\omega'')|^2 \rangle}}$$

$$g_2(\omega', \omega'') = \frac{\langle |\tilde{E}(\omega')|^2 |\tilde{E}(\omega'')|^2 \rangle}{\langle |\tilde{E}(\omega')|^2 \rangle \langle |\tilde{E}(\omega'')|^2 \rangle}$$

$$|g_1(\omega', \omega'')| = \frac{|\tilde{X}(\omega' - \omega'')|}{\tilde{X}(0)}$$

Valid in the linear regime

$$g_2(\omega', \omega'') = 1 + |g_1(\omega', \omega'')|^2$$

For non-linear regime, we run numerical simulations

Model description

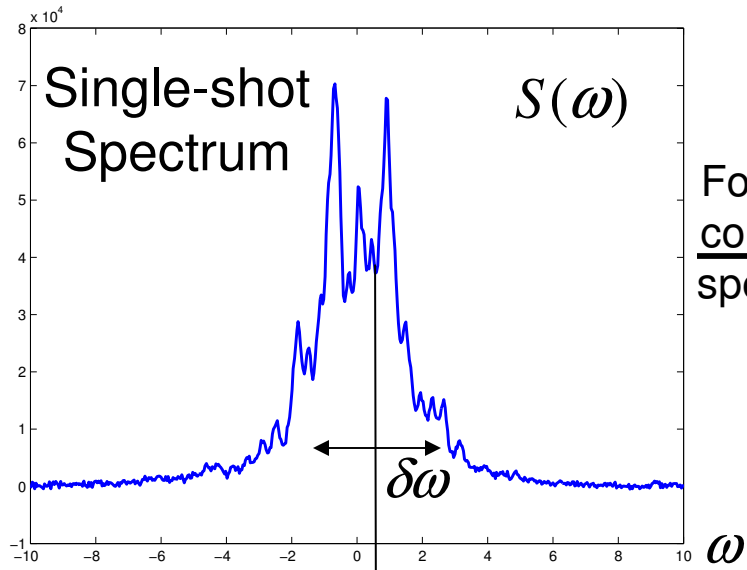
Correlation of the intensity at the exit of the spectrometer

$$G_2(\delta\omega) = \frac{\langle S(\omega_0 + \delta\omega/2) S(\omega_0 - \delta\omega/2) \rangle}{\langle S(\omega_0 + \delta\omega/2) \rangle \langle S(\omega_0 - \delta\omega/2) \rangle} - 1$$

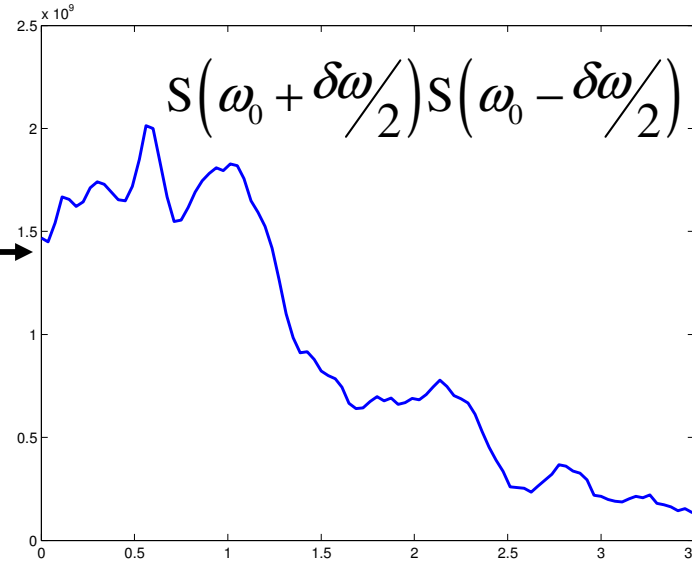
$S(\omega)$ Intensity spectrum at frequency ω

ω_0 Central frequency of amplification

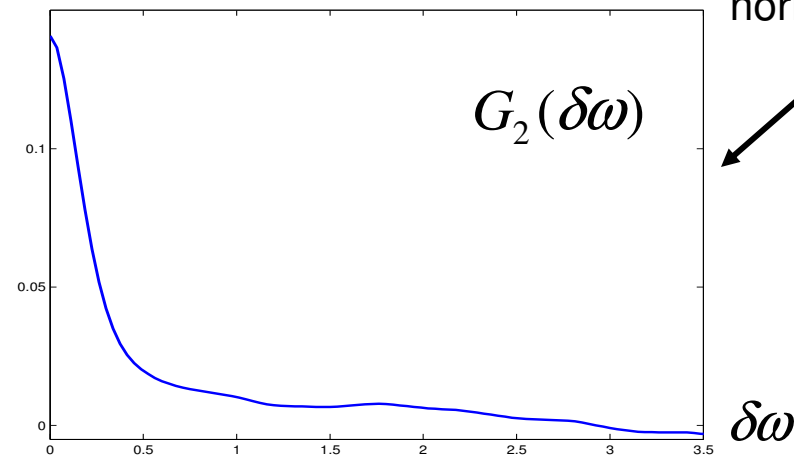
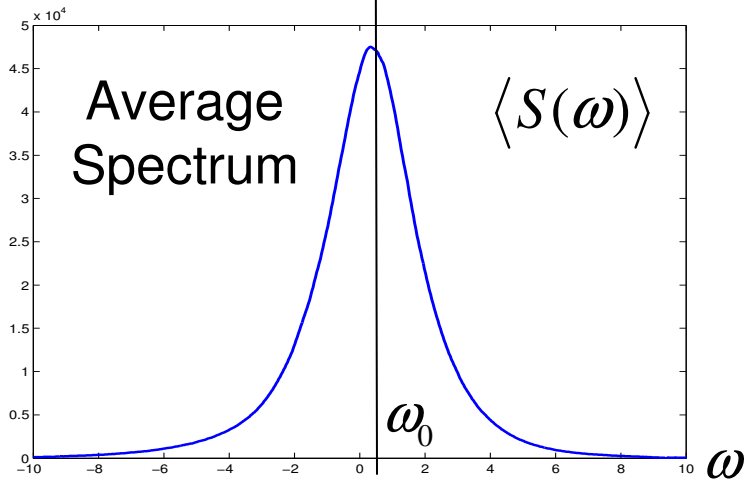
Procedure to calculate G_2



For each collected spectrum



Average on many shots
And normalization



G₂ function for different X(t) profiles

$$\left| \tilde{H}_{ti}(\omega) \right|^2 \propto e^{-\frac{(\omega - \omega_0)^2}{2\sigma_a^2 \omega_0^2}} \quad \sigma_a \text{ relative FEL bandwidth}$$

We assume that the spectrometer has Gaussian resolution function

$$\sigma_m \text{ relative rms spectrometer resolution}$$

$$G_2(\delta\omega) = \int_{-\infty}^{+\infty} \frac{e^{-\frac{(\zeta - \delta\omega\xi_0)^2}{2\sigma^2}} \left| \tilde{X}(\zeta, T) \right|^2}{\sqrt{2\pi\sigma}} d\zeta$$

$$\xi_0 = \frac{\sigma_a^2}{\sigma_m^2 + \sigma_a^2} \omega_0$$

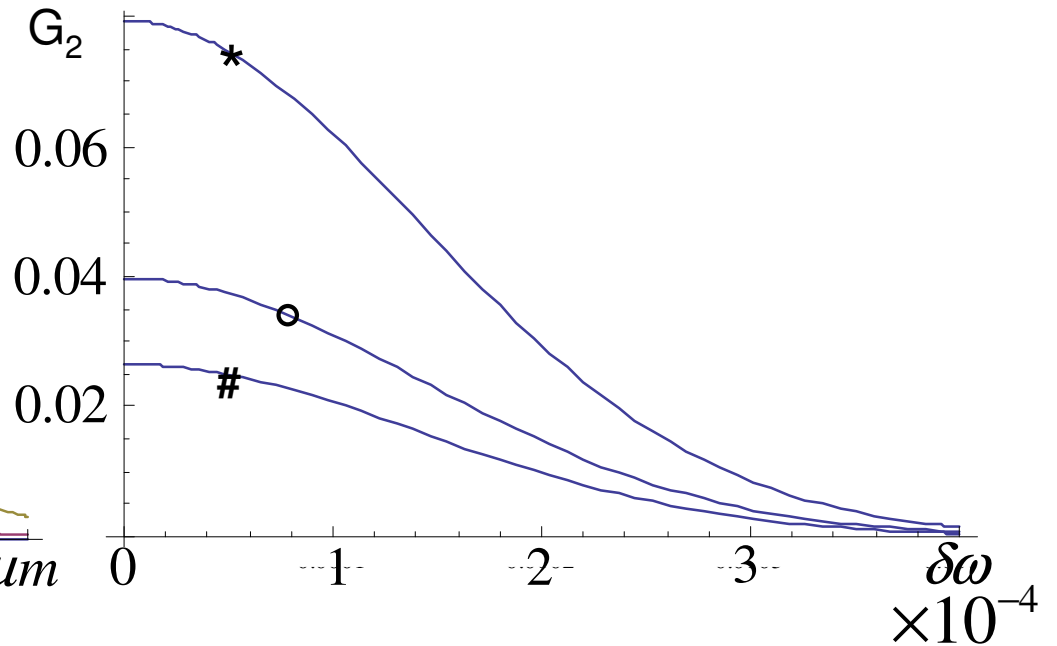
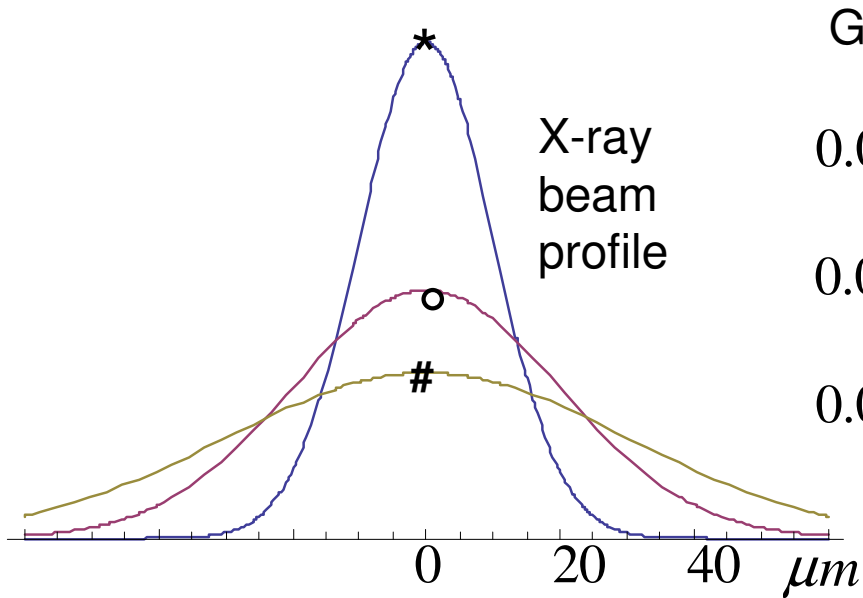
$$\sigma = \sqrt{2} \frac{\sigma_a \sigma_m}{\sqrt{\sigma_m^2 + \sigma_a^2}} \omega_0$$

To find an analytical expression for G₂ we need just to plug in the X(t) average profile

G₂ with Gaussian profile

$$X(t, \sigma_T) = \frac{e^{-\frac{t^2}{2\sigma_T^2}}}{\sqrt{2\pi}\sigma_T}$$

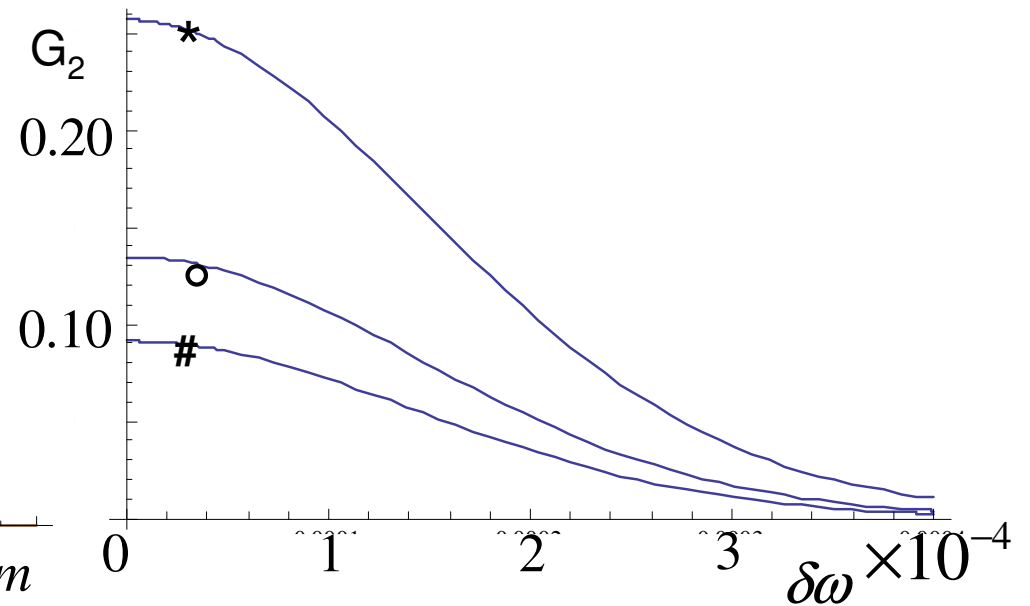
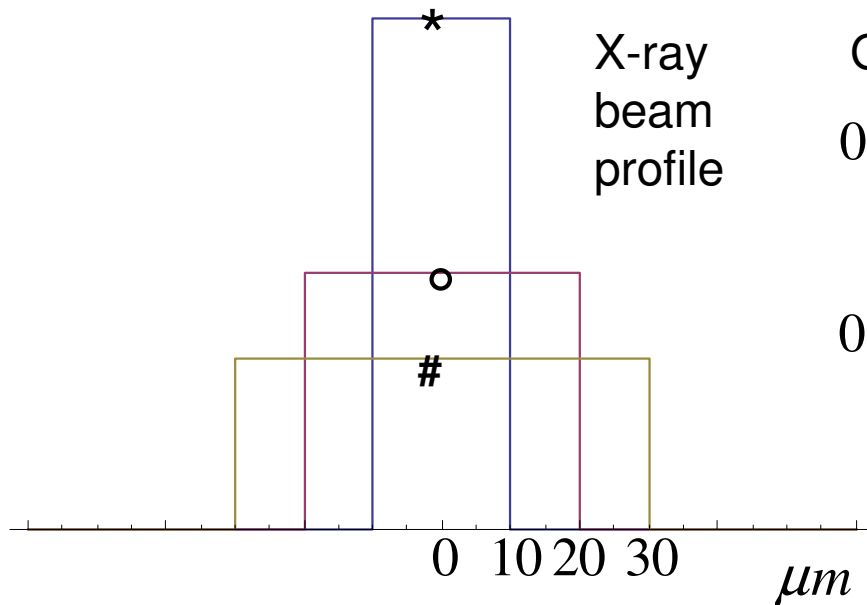
$$G_2(\delta\omega) = \frac{e^{-\frac{\delta\omega^2 \xi_0^2 \sigma_t^2}{1+2\sigma^2 \sigma_t^2}}}{\sqrt{1+2\sigma^2 \sigma_t^2}}$$



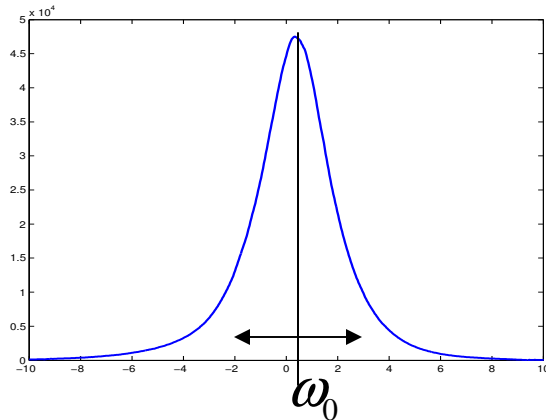
G₂ with flat top profile

$$X(t, T) = \begin{cases} 1/T & |t| \leq T/2 \\ 0 & |t| > T/2 \end{cases}$$

$$G_2(\delta\omega) = 2 \int_0^1 e^{-\frac{\zeta^2 \sigma^2 T^2}{2}} (1 - \zeta) \cos(\delta\omega \xi_0 T \zeta) d\zeta$$



Non stationary ω_0 and FEL gain jitter



Central frequency jitters with
Gaussian law with rms $\sigma_\omega \omega_0$

$$G_2(\delta\omega) = K(\delta\omega) \int_{-\infty}^{+\infty} \frac{e^{-\frac{(\zeta - \delta\omega \xi_0)^2}{2\sigma^2}} |\tilde{X}(\zeta, T)|^2}{\sqrt{2\pi\sigma}} d\zeta$$

$$K(\delta\omega) = \frac{(\sigma_a^2 + \sigma_m^2 + \sigma_\omega^2) e^{-\frac{\delta\omega^2 \sigma_\omega^2}{4(\sigma_a^2 + \sigma_m^2)(\sigma_a^2 + \sigma_m^2 + \sigma_\omega^2)}}}{\sqrt{(\sigma_a^2 + \sigma_m^2)(\sigma_a^2 + \sigma_m^2 + \sigma_\omega^2)}}$$

Non stationary ω_0 and FEL gain jitter

Shot to shot gain as random variable with average \bar{G}

correlate spectral intensities $I' = (\bar{G} + \Delta G)(\bar{S}' + \Delta S')$ at ω'
 $I'' = (\bar{G} + \Delta G)(\bar{S}'' + \Delta S'')$ at ω''

$$\frac{\langle I' I'' \rangle}{\langle I' \rangle \langle I'' \rangle} = \left(1 + \frac{\langle \Delta S' \Delta S'' \rangle}{\bar{S}' \bar{S}''} \right) \left(1 + \frac{\langle \Delta G^2 \rangle}{\bar{G}^2} \right)$$

$$G_2(\omega', \omega'') = \frac{\frac{\langle I' I'' \rangle}{\langle I' \rangle \langle I'' \rangle}}{1 + \frac{\langle \Delta G^2 \rangle}{\bar{G}^2}} - 1$$

Numerical simulations

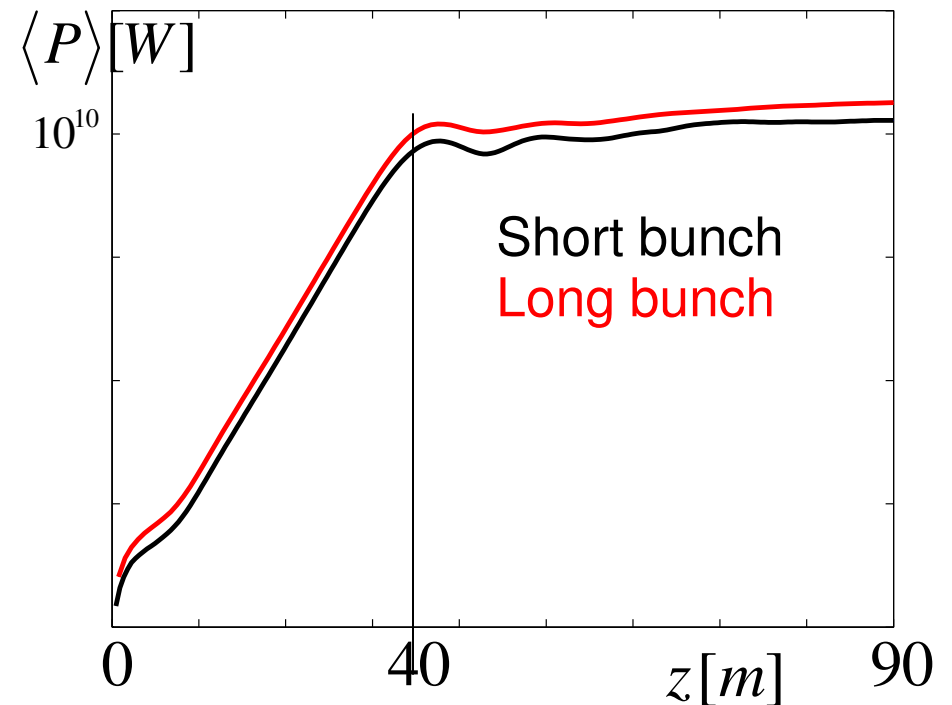
- 1) Verify that relations hold well enough in saturation
- 2) Recover bunch length and spectrometer resolution

- $30\mu\text{m}$ electron bunch
- $3\mu\text{m}$ electron bunch

Wavelength 0.8 nm

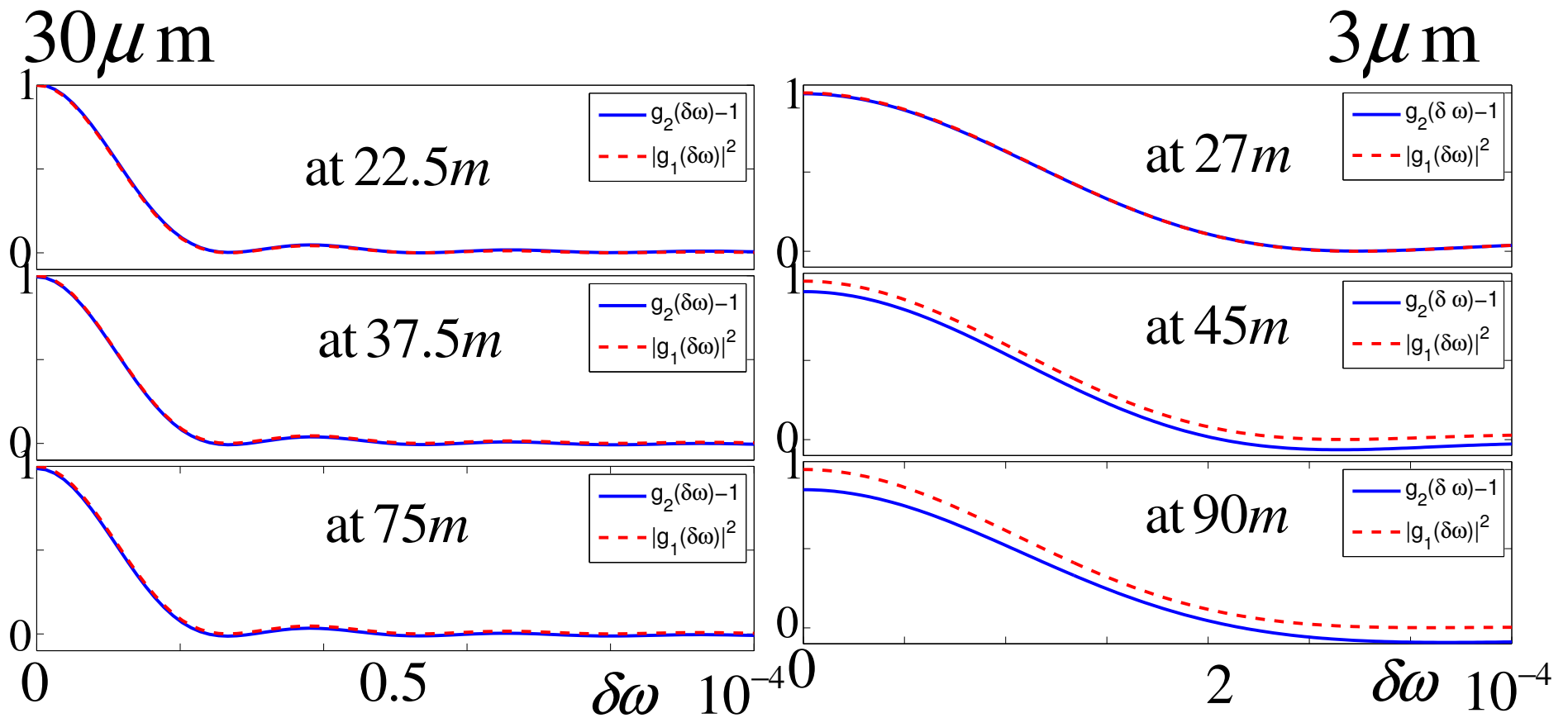
Undulator period 3 cm

- $\sigma_m = 1 \times 10^{-4}$
- $\sigma_m = 2 \times 10^{-4}$

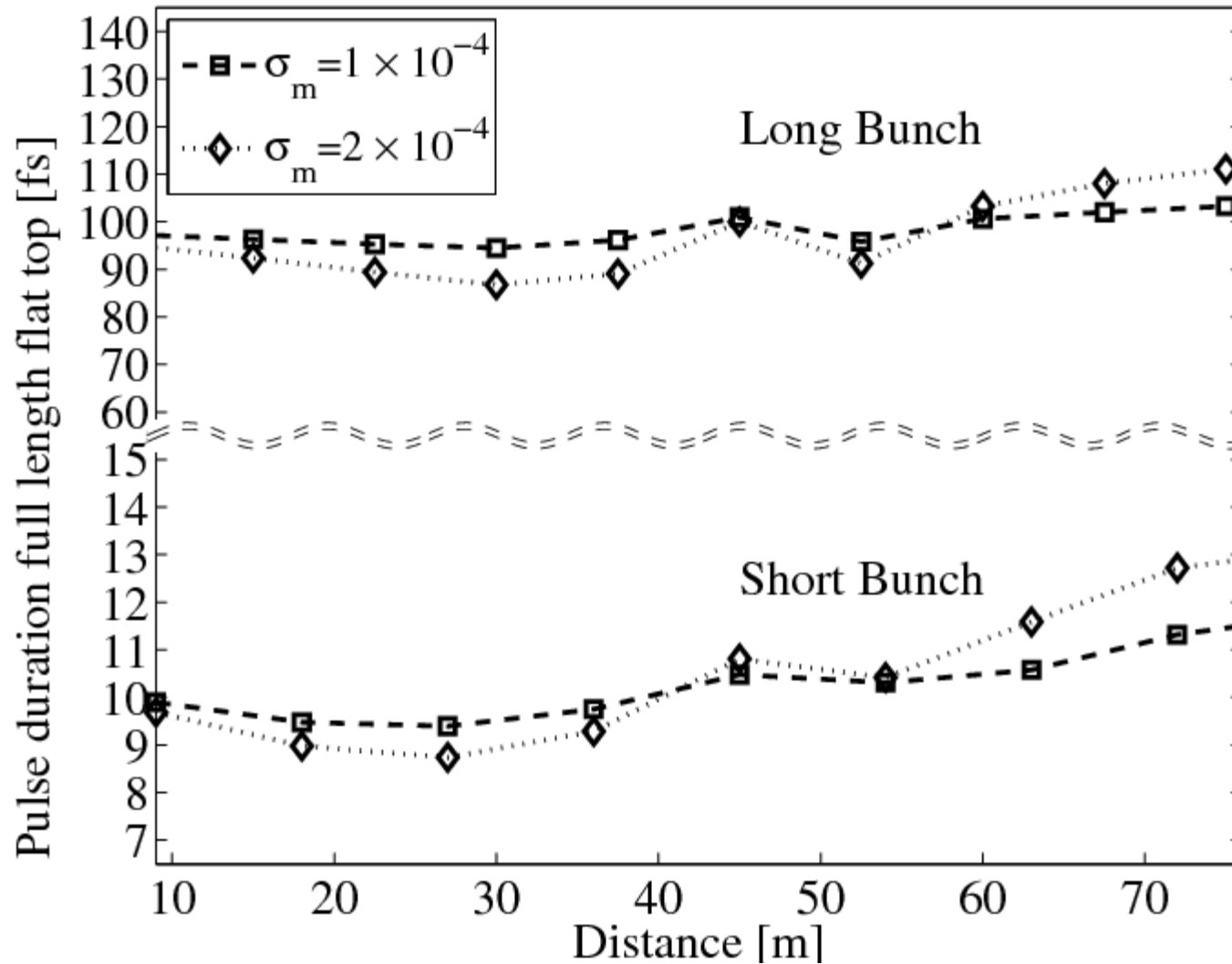


Verify relation

$$g_2(\omega', \omega'') - 1 = |g_1(\omega', \omega'')|^2$$



Simulated measurements results



Retrieved spectrometer resolutions

Long bunch
 $(1.01 \pm 0.01) \times 10^{-4}$
 $(2.05 \pm 0.05) \times 10^{-4}$

Short bunch
 $(0.98 \pm 0.03) \times 10^{-4}$
 $(1.98 \pm 0.09) \times 10^{-4}$

Experimental results

Experimental demonstration performed at LCLS

Photon energy 1.5 keV

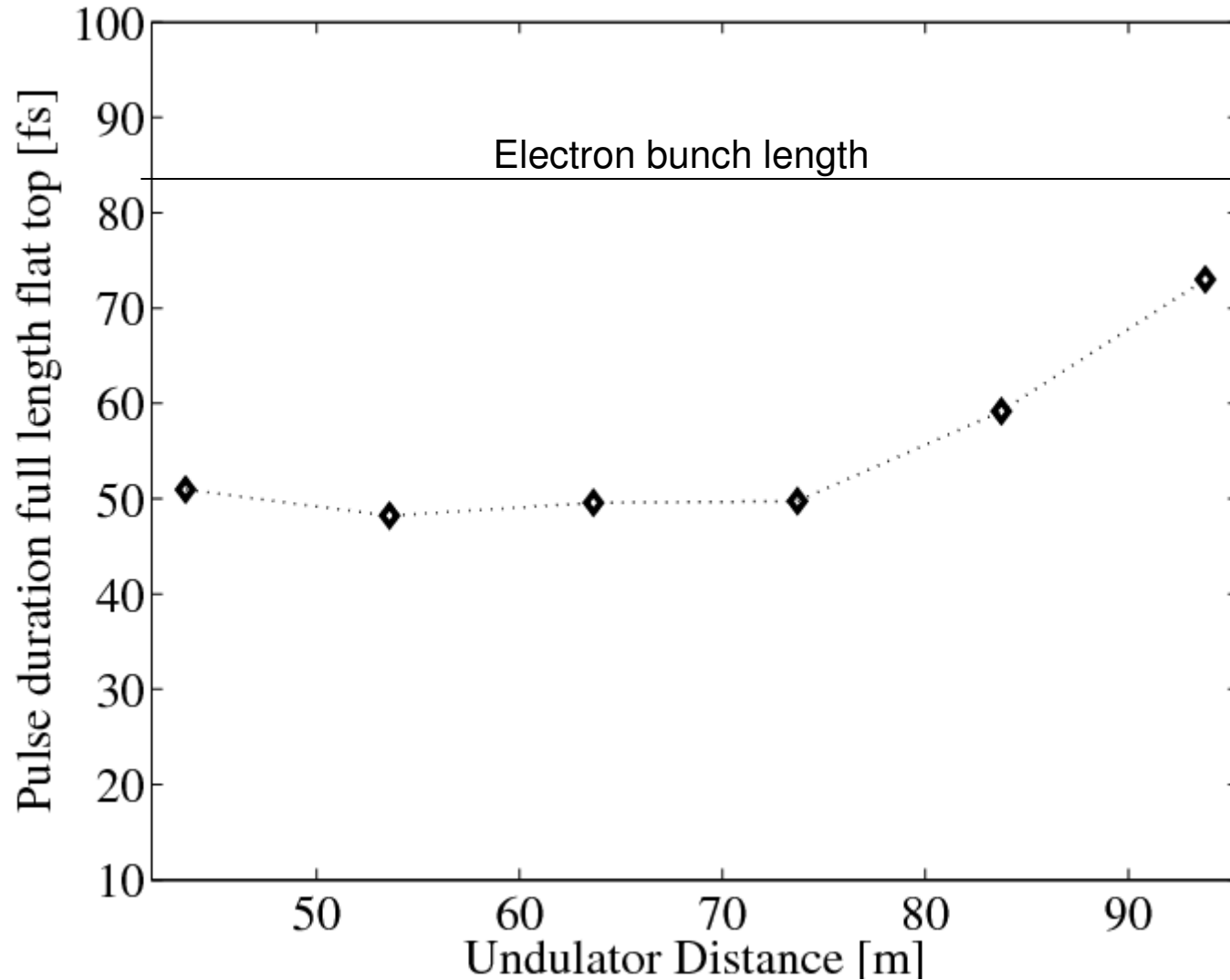
Electron charge 250 pC

Different undulator length

Different peak current

Controlling lasing part of electron bunch with slotted foil

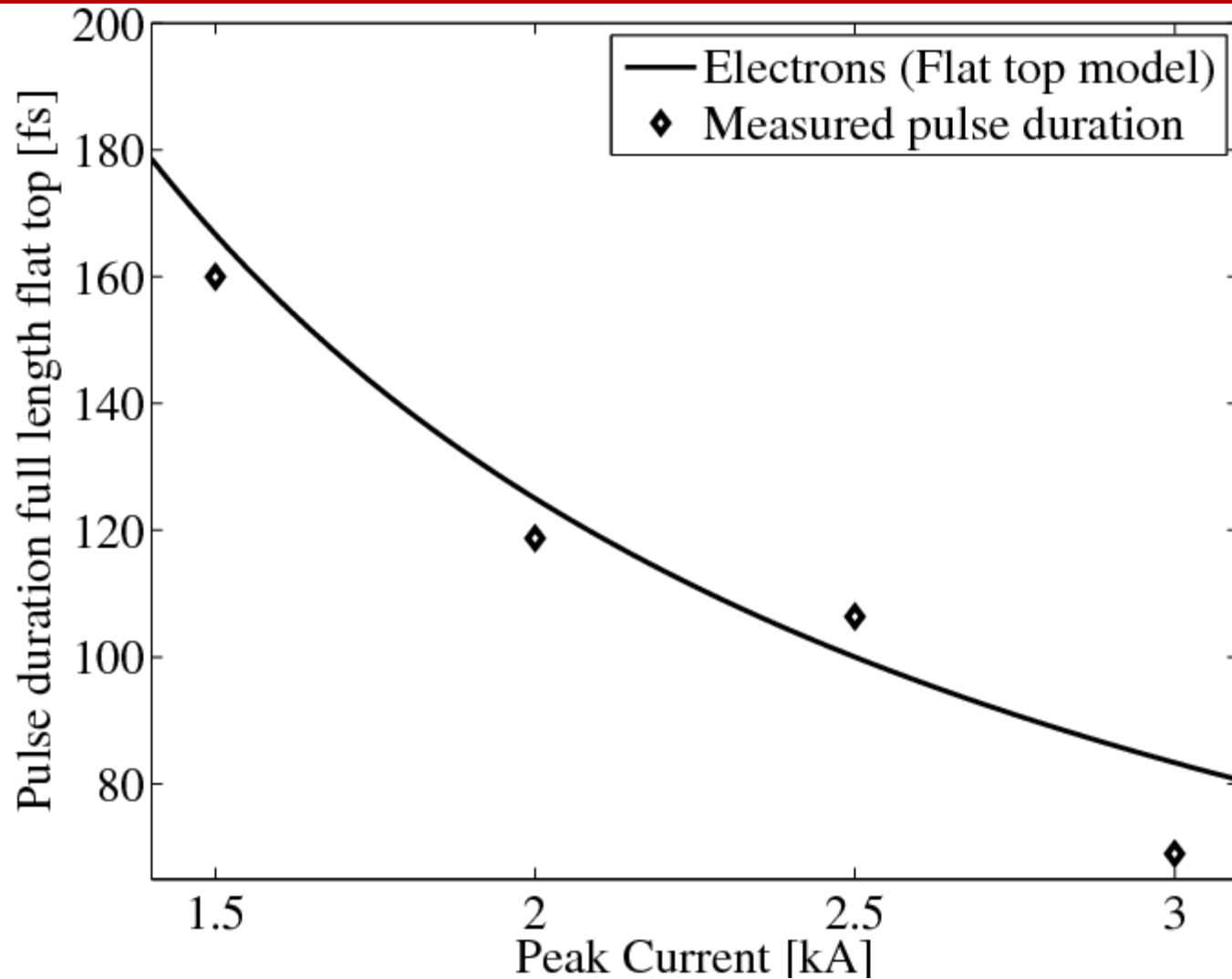
Different undulators distance



Measured spectrometer relative resolution σ_m
 $(1.00 \pm 0.04) \times 10^{-4}$

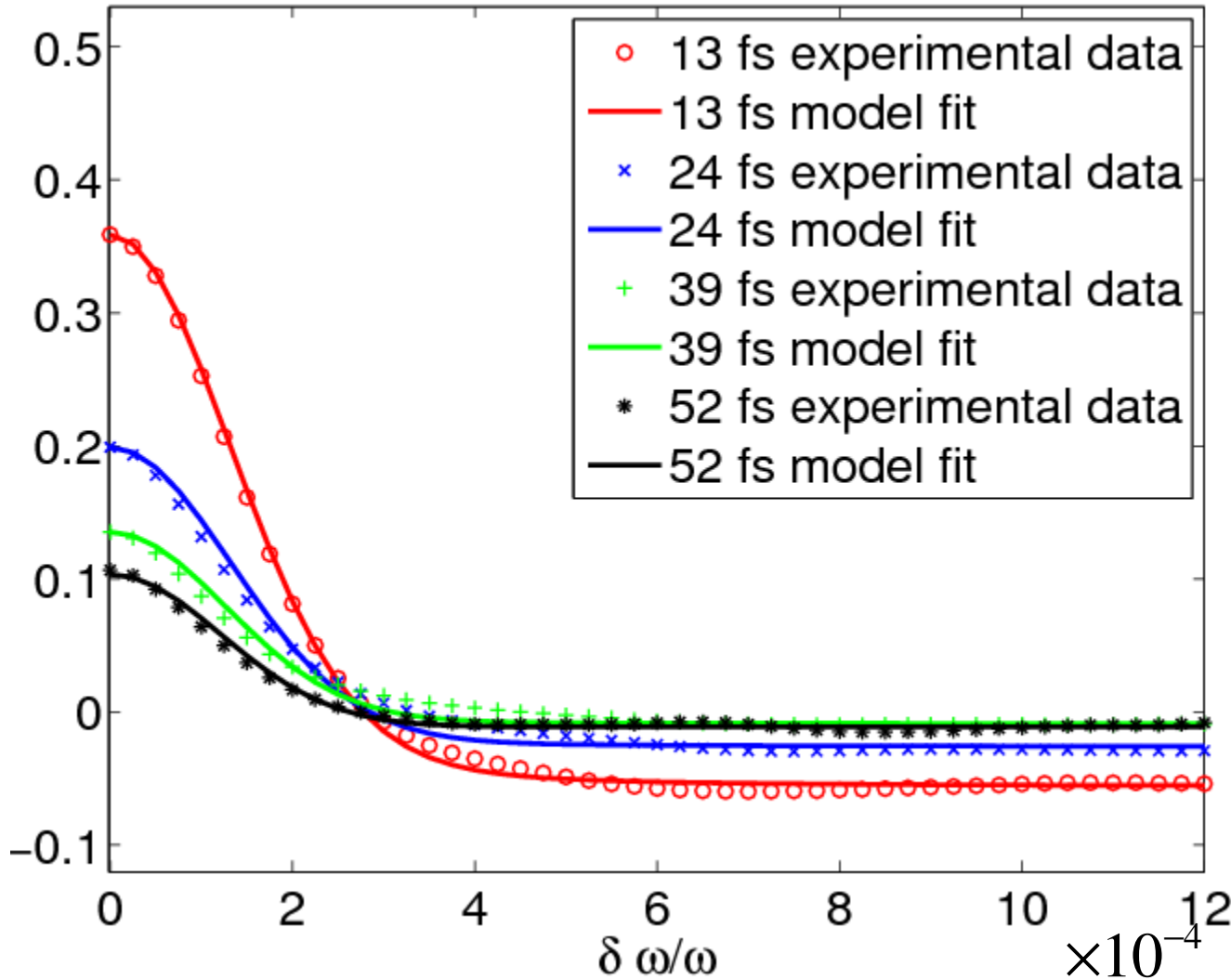
Measured x-rays are shorter than the electron bunch

Different peak currents



Measured x-rays pulse durations are consistent with electron bunch length change.

Slotted foil measurements



Electron bunch FWHM	x-ray FWHM
10 fs	13 fs
18 fs	24 fs
27 fs	39 fs
56 fs	52 fs

Thank you for your attention